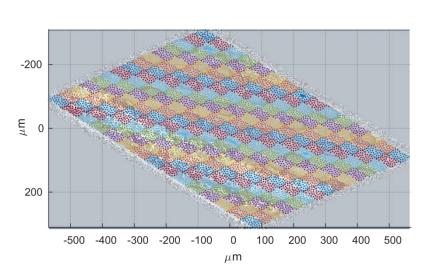


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Supporting information for article:

LamNI – an instrument for X-ray scanning microscopy in laminography geometry

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LamNI – an instrument for X-ray scanning microscopy in laminography geometry

Figure S1 A demonstration of the stitching capability of the instrument. The figure shows a single projection with a square shape about $(0.5 \text{mm})^2$ in size in the sample plane. The data was acquired by scanning many smaller areas using the Piezo stage and stitching such scans using the coarse stages. The individual sub-scans are indicated by differently colored symbols.

Supporting Figures